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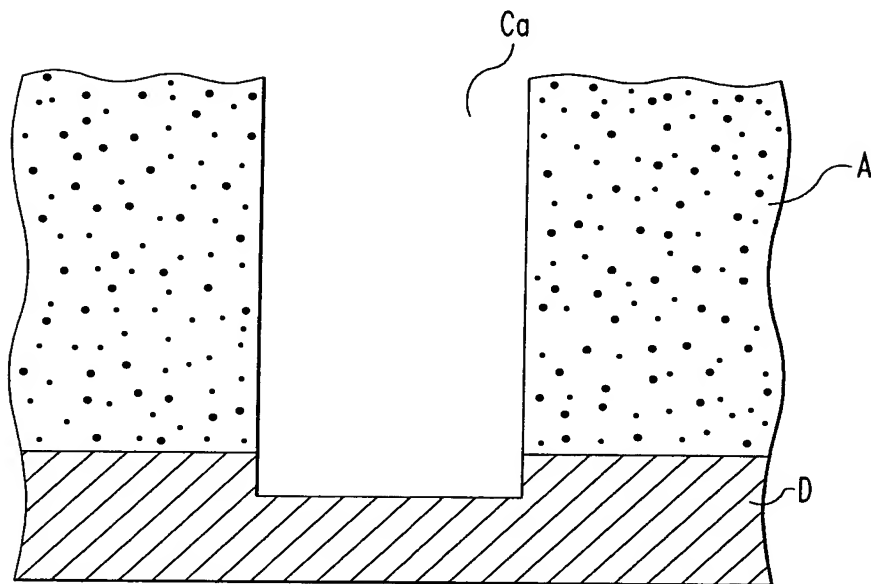


FIG.1(a)

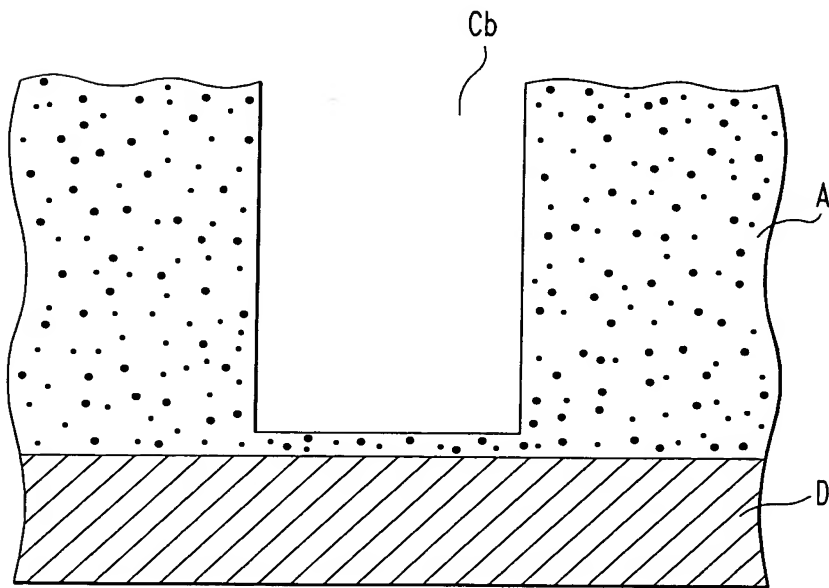
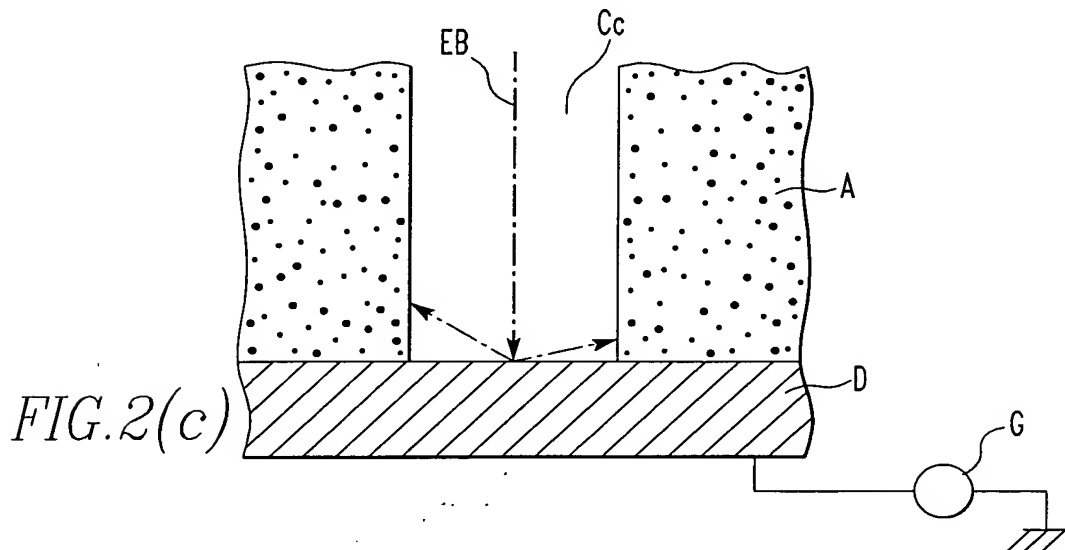
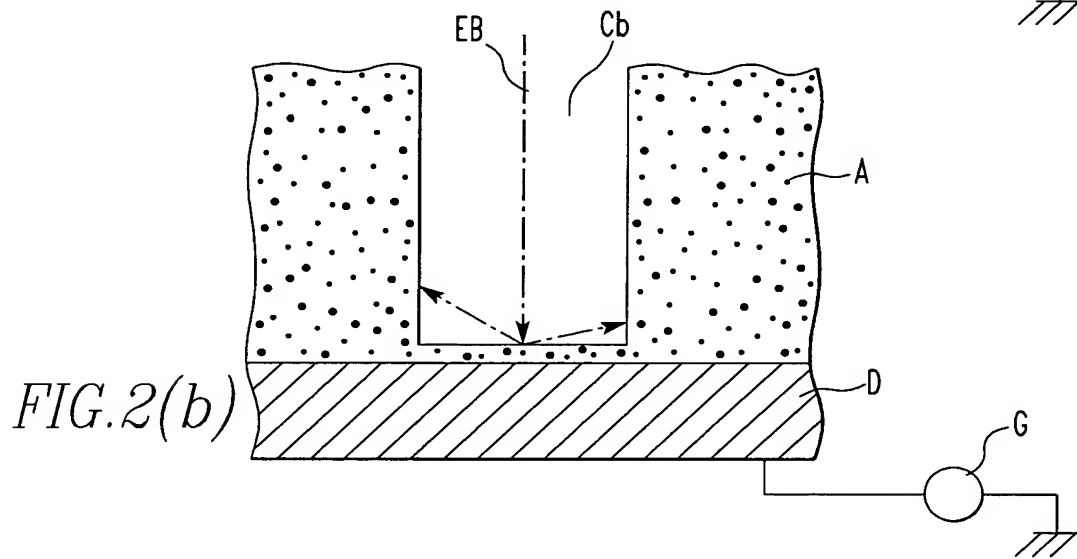
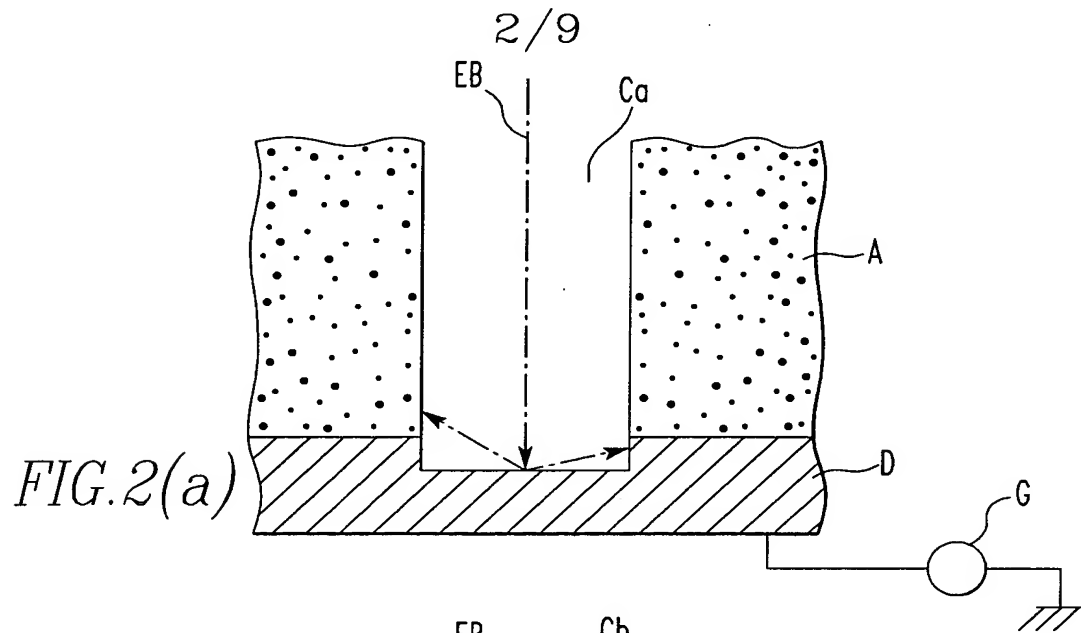


FIG.1(b)

"Method of Inspecting Holes Using Charged-Particle Beam"

Inventors: Naoki KIKUCHI et al.

Serial No. 10/060,944



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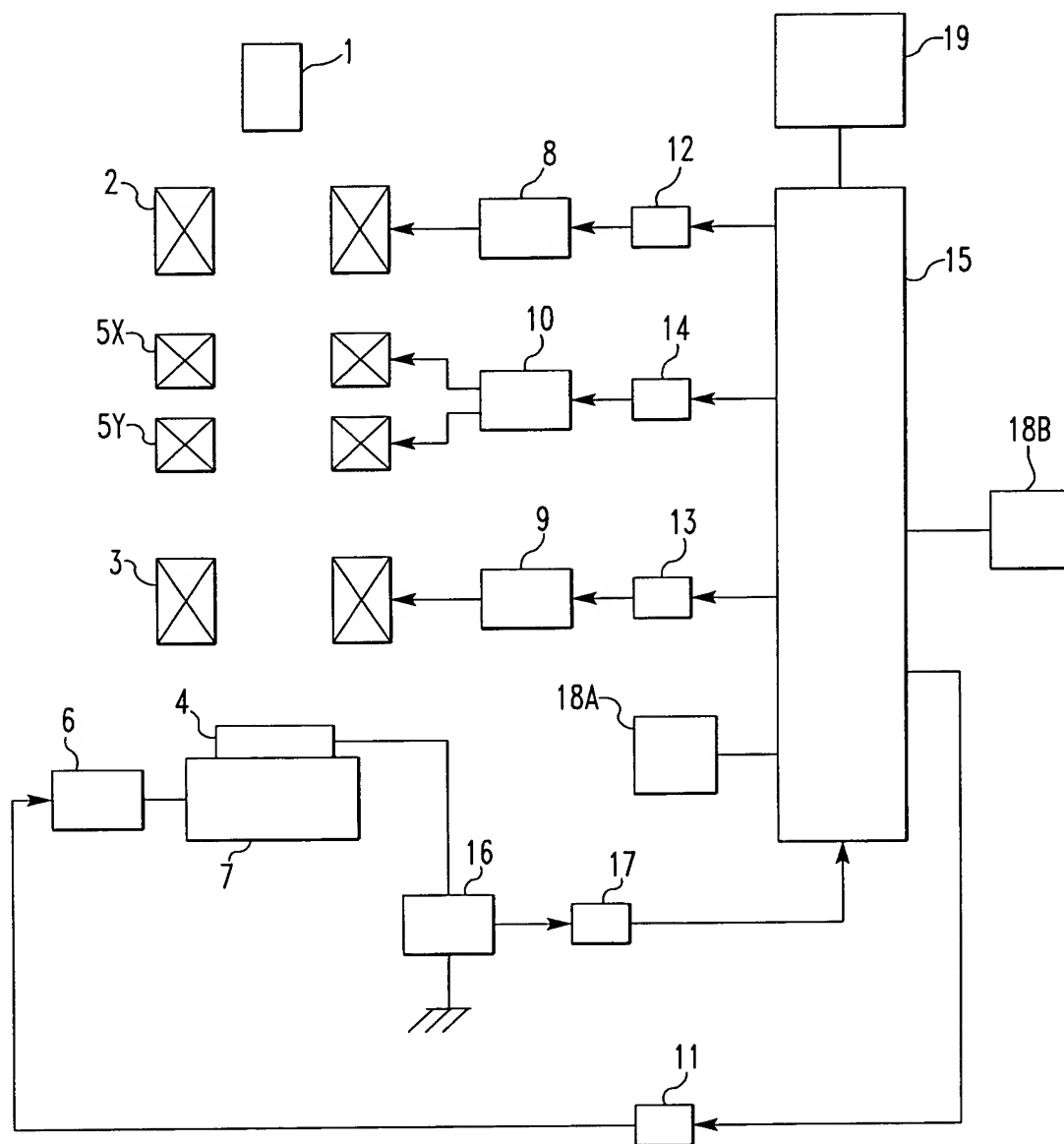


FIG. 3

"Method of Inspecting Holes Using Charged-Particle Beam"

Inventors: Naoki KIKUCHI et al.

Serial No. 10/060,944

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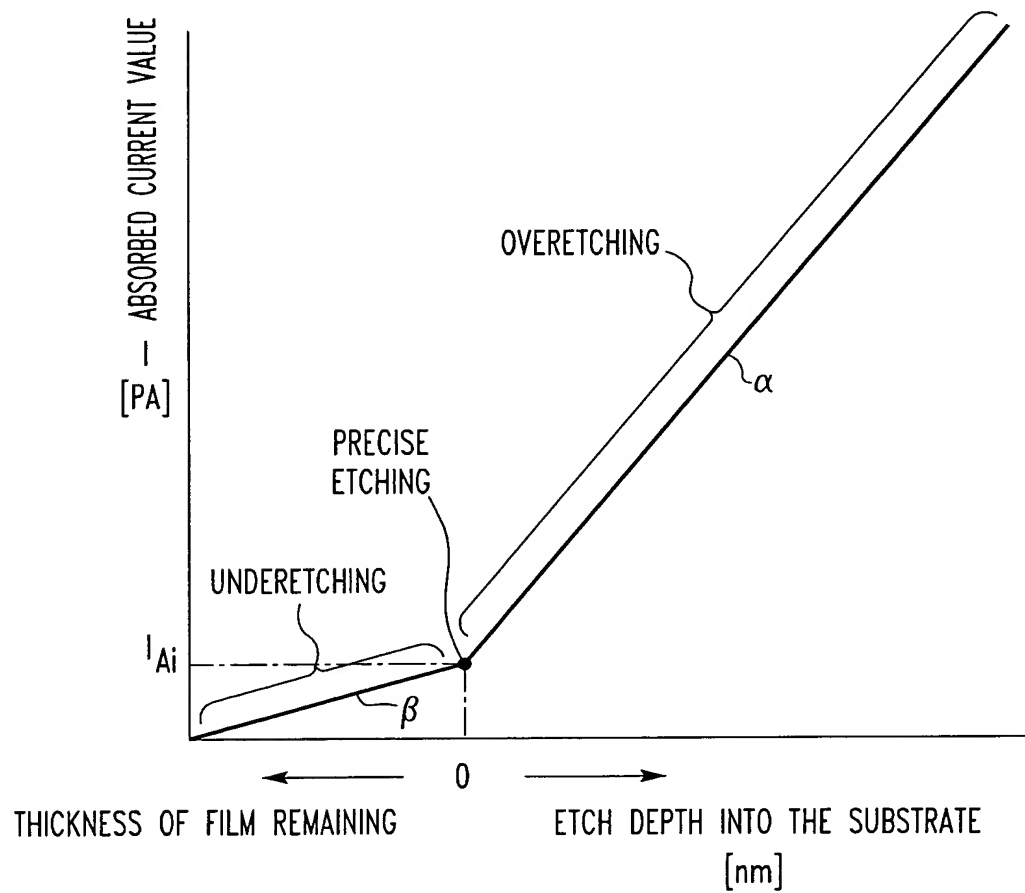


FIG. 4

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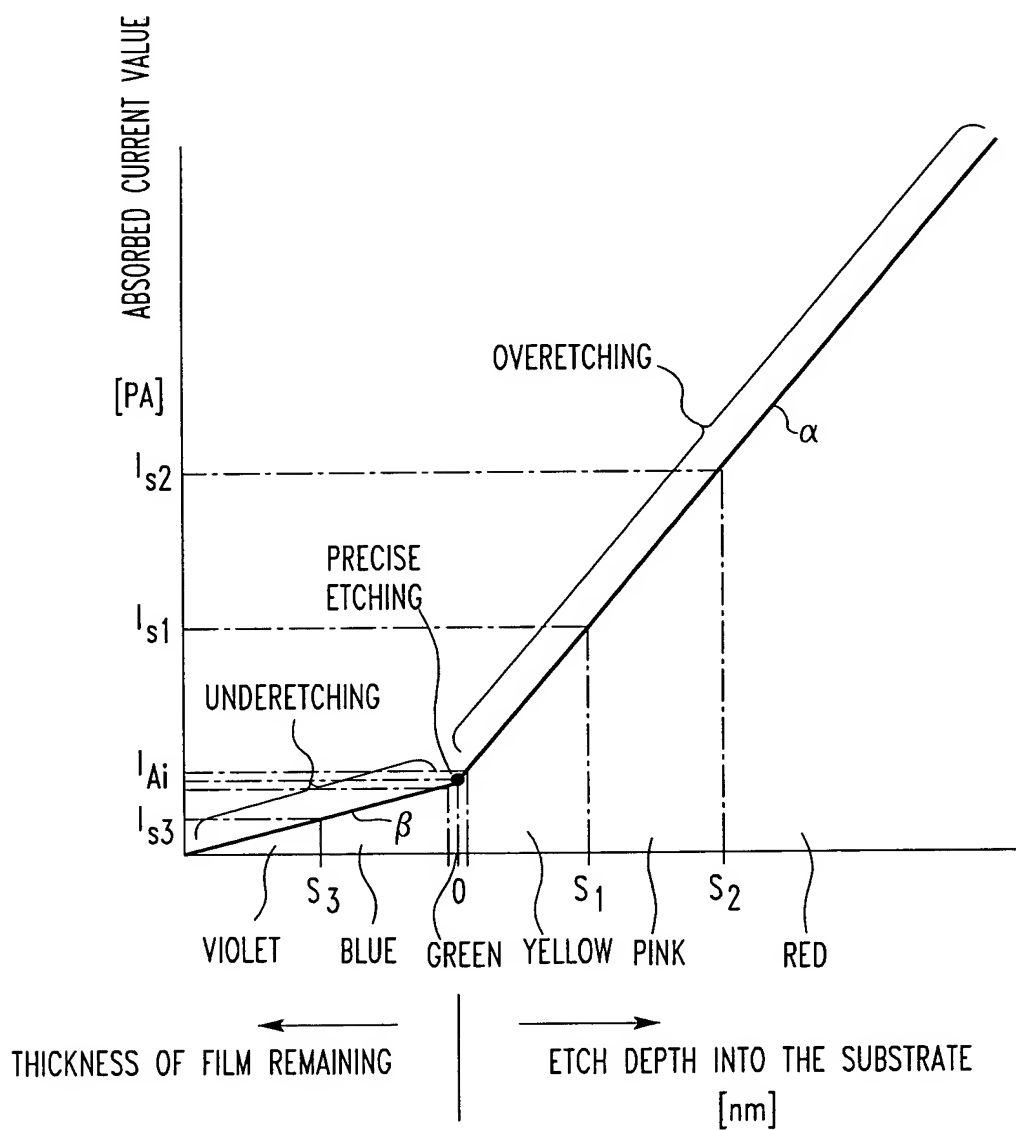


FIG.5

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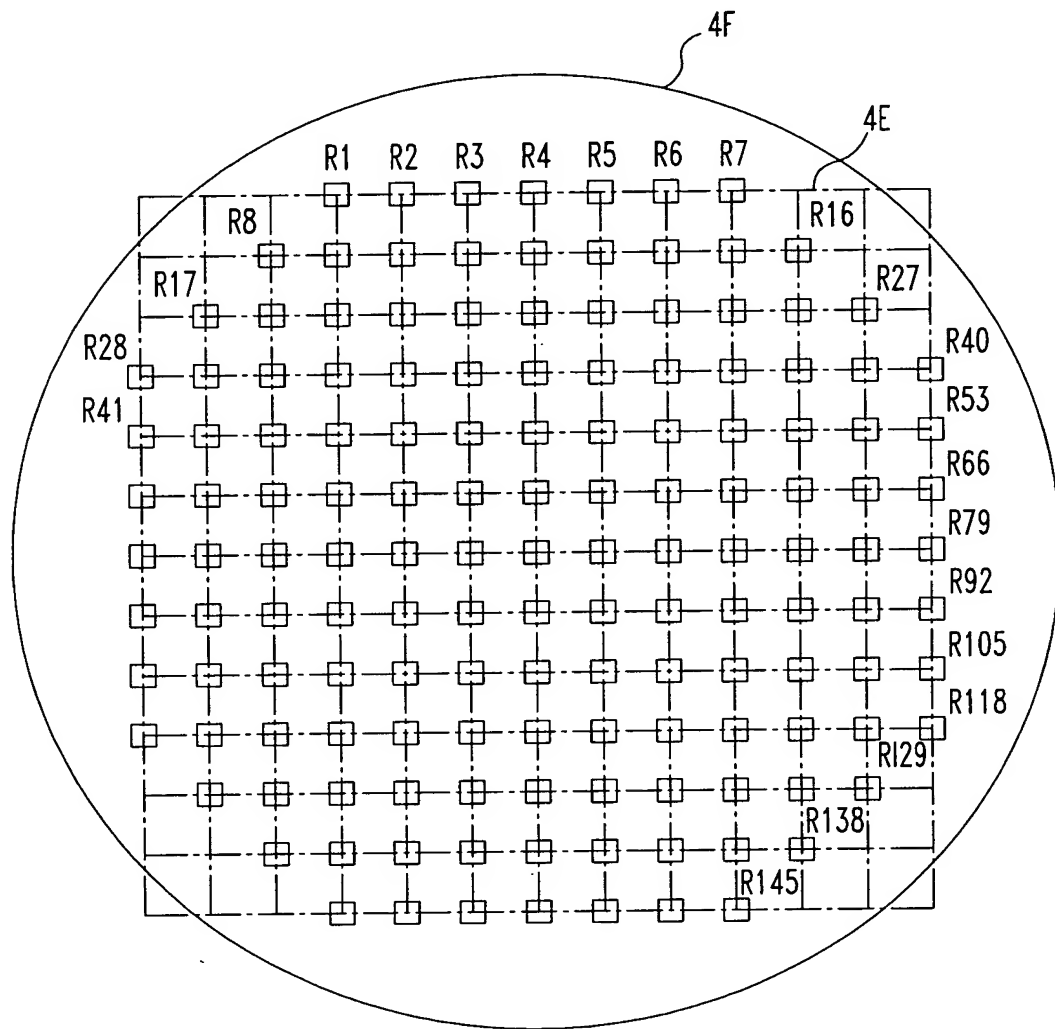


FIG. 6

"Method of Inspecting Holes Using Charged-Particle Beam"

Inventors: Naoki KIKUCHI et al.

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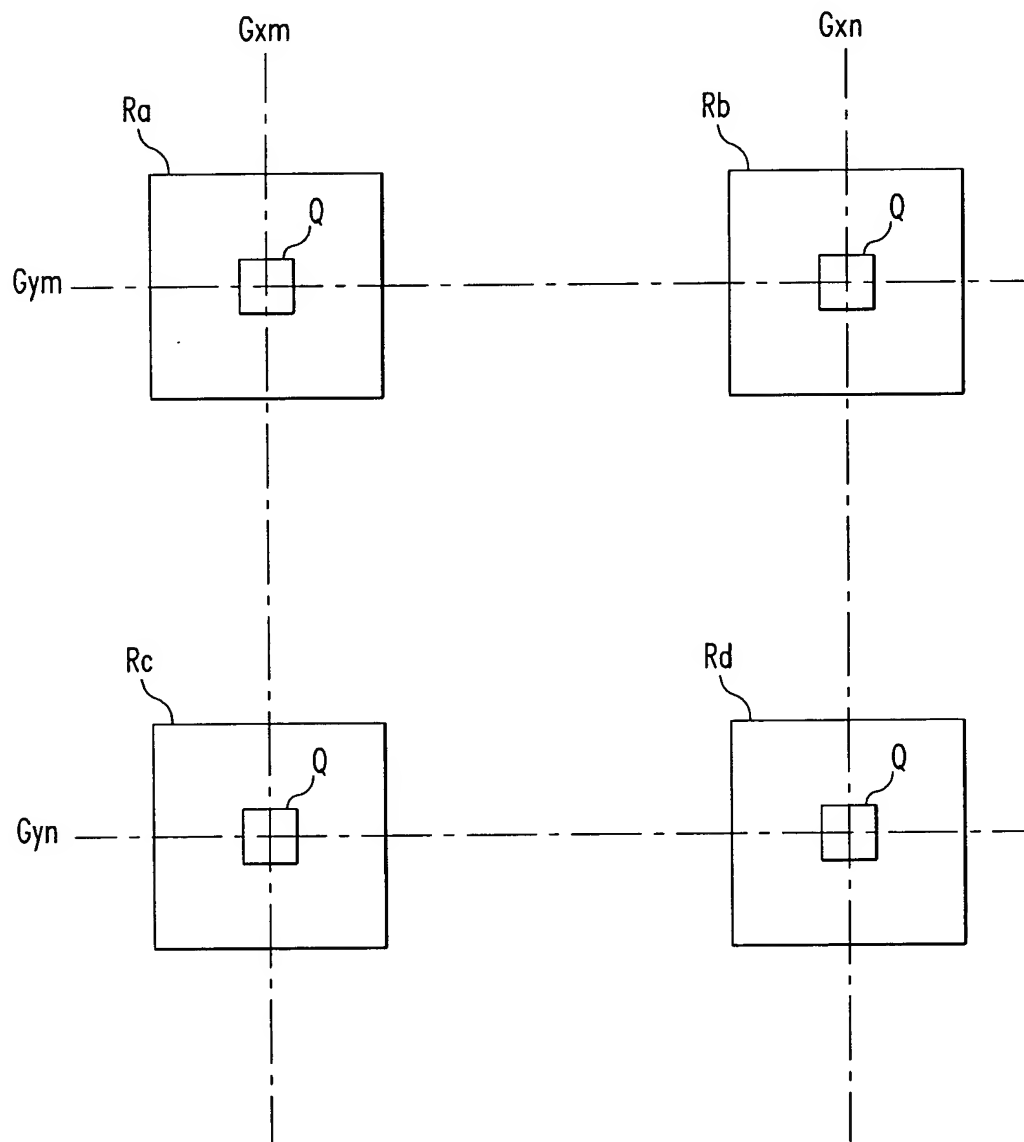


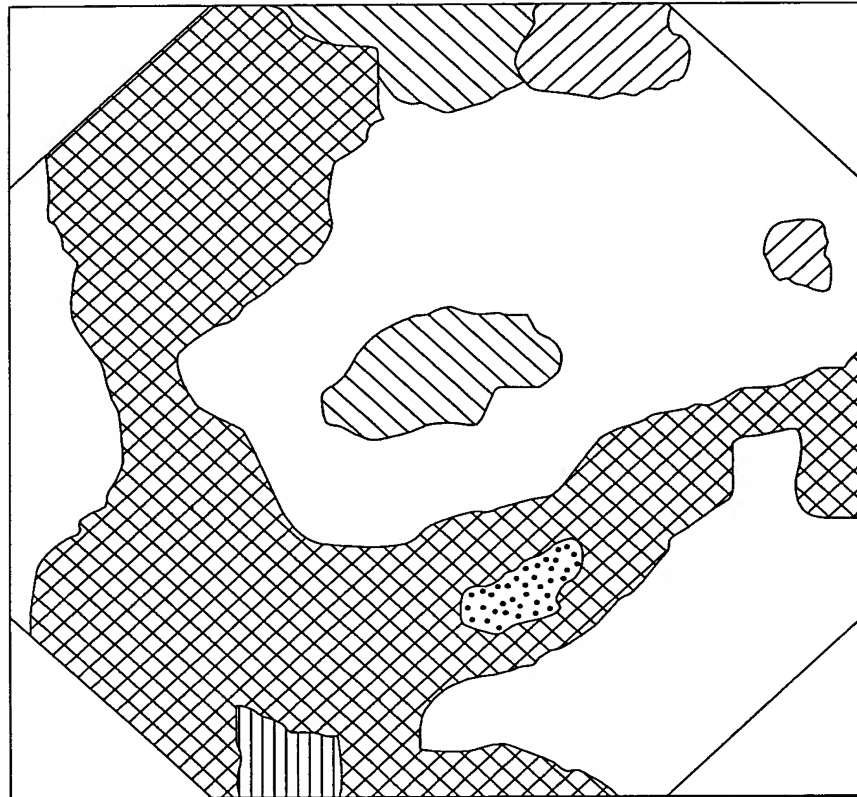
FIG. 7

"Method of Inspecting Holes Using Charged-Particle Beam"

Inventors: Naoki KIKUCHI et al.

Serial No. 10/060,944

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RED



GREEN



PINK



BLUE



YELLOW



VIOLET

FIG. 8



"Method of Inspecting Holes Using Charged-Particle Beam"

Inventors: Naoki KIKUCHI et al.

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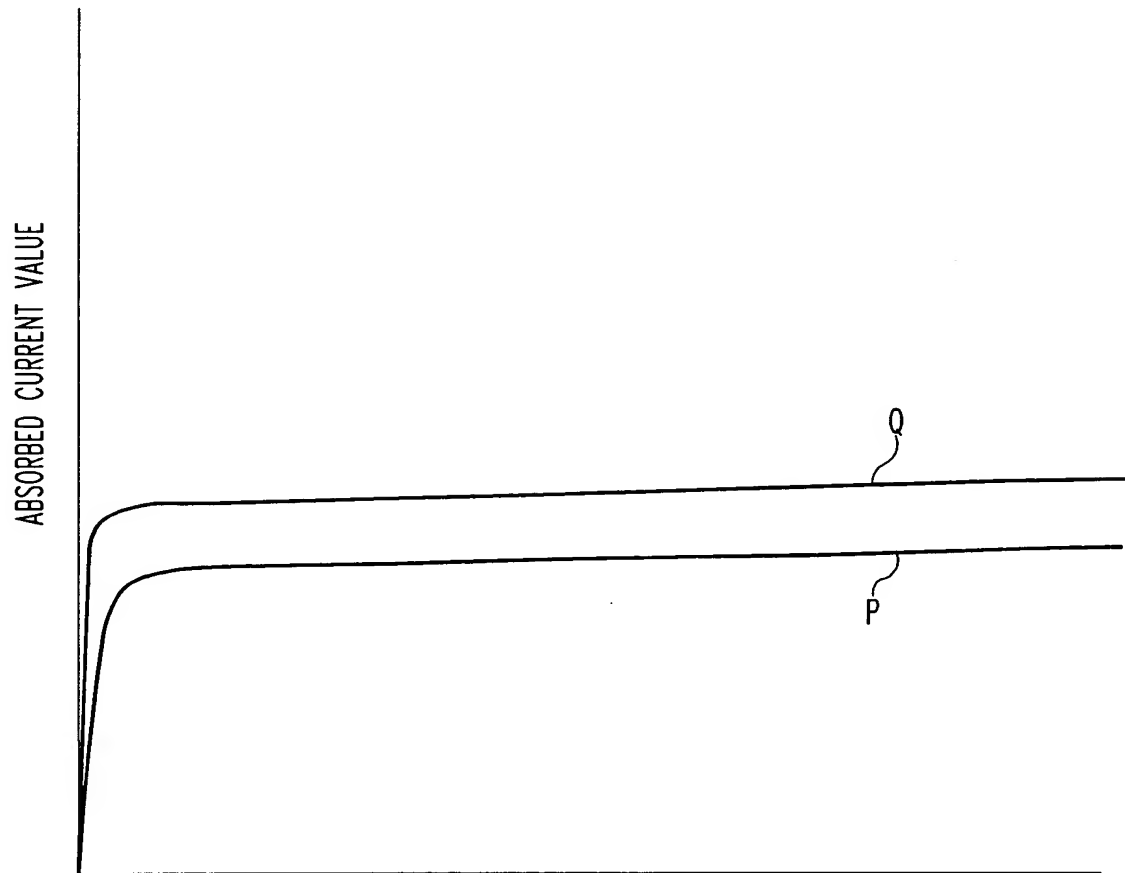


FIG. 9